

INTERNATIONAL SEARCH REPORT

International Application No
PCT/IB2005/050343

A. CLASSIFICATION OF SUBJECT MATTER
IPC 7 G01R31/30 G01R31/3161 G01R31/3167

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
IPC 7 G01R

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	DALMIA M ET AL: "Power supply current monitoring techniques for testing PLLs" TEST SYMPOSIUM, 1997. (ATS '97). PROCEEDINGS., SIXTH ASIAN AKITA, JAPAN 17-19 NOV. 1997, LOS ALAMITOS, CA, USA, IEEE COMPUT. SOC, US, 17 November 1997 (1997-11-17), pages 366-371, XP010258753 ISBN: 0-8186-8209-4 the whole document ----- -/--	1-18

☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

* Special categories of cited documents:

- *A* document defining the general state of the art which is not considered to be of particular relevance
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

- *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
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Date of the actual completion of the international search

29 April 2005

Date of mailing of the international search report

10/05/2005

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	<p>BEASLEY J S ET AL: "IDD pulse response testing on analog and digital CMOS circuits"</p> <p>TEST CONFERENCE, 1993. PROCEEDINGS., INTERNATIONAL BALTIMORE, MD, USA 17-21 OCT. 1993, NEW YORK, NY, USA, IEEE, 17 October 1993 (1993-10-17), pages 626-634, XP010148193</p> <p>ISBN: 0-7803-1430-1</p> <p>the whole document</p>	1-18
A	<p>A'AIN A K B ET AL: "Testing analogue circuits by AC power supply voltage"</p> <p>VLSI DESIGN, 1996. PROCEEDINGS., NINTH INTERNATIONAL CONFERENCE ON BANGALORE, INDIA 3-6 JAN. 1996, LOS ALAMITOS, CA, USA, IEEE COMPUT. SOC, US, 3 January 1996 (1996-01-03), pages 238-241, XP010157136</p> <p>ISBN: 0-8186-7228-5</p> <p>the whole document</p>	1-18
A	<p>EP 1 286 169 A (FUJITSU LIMITED)</p> <p>26 February 2003 (2003-02-26)</p> <p>paragraph '0025! - paragraph '0035!;</p> <p>figures 6,9</p>	1-18
A	<p>KIM S ET AL: "An effective defect-oriented BIST architecture for high-speed phase-locked loops"</p> <p>VLSI TEST SYMPOSIUM, 2000. PROCEEDINGS. 18TH IEEE MONTREAL, QUE., CANADA 30 APRIL-4 MAY 2000, LOS ALAMITOS, CA, USA, IEEE COMPUT. SOC, US, 30 April 2000 (2000-04-30), pages 231-236, XP010502233</p> <p>ISBN: 0-7695-0613-5</p> <p>the whole document</p>	1-18

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

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Patent document cited in search report		Publication date		Patent family member(s)	Publication date
EP 1286169	A	26-02-2003	JP	2003069423 A	07-03-2003
			EP	1286169 A2	26-02-2003
			US	2003038619 A1	27-02-2003
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